- Package Options Include Plastic Small Outline Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs
- Dependable Texas Instruments Quality and Reliability

#### description

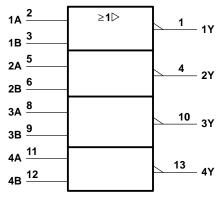
These devices contain four independent 2-input NOR buffer gates. They perform the Boolean functions  $Y = \overline{A} + \overline{B}$  or  $Y = \overline{A} \bullet \overline{B}$  in positive logic.

The SN54ALS28A is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74ALS28A is characterized for operation from 0°C to 70°C.

FUNCTION TABLE (each gate)

INP	UTS	OUTPUT				
Α	В	Y				
Н	Χ	L				
Х	Н	L				
L	L	Н				

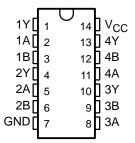
## logic symbol†



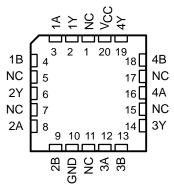
<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std –1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, and N packages.

#### SN54ALS28A . . . J PACKAGE SN74ALS28A . . . D OR N PACKAGE (TOP VIEW)

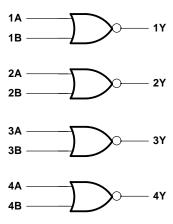


## SN54ALS28A . . . FK PACKAGE (TOP VIEW)



NC-No internal connection

## logic diagram (positive logic)



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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V <sub>CC</sub>		7 V
Input voltage		7 V
	SN54ALS28A	
	SN74ALS28A	0°C to 70°C
Storage temperature range		-65°C to 150°C

#### recommended operating conditions

		SN54ALS28A		SN74ALS28A			UNIT	
		MIN	NOM	MAX	MIN	NOM	MAX	Oitii
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
V <sub>IL</sub>	Low-level input voltage			0.7			0.8	V
Vон	High-level output current			-1			-2.6	mA
lOL	Low-level output current			12			24	mA
TA	Operating free-air temperature	-55		125	0		70	°C

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST CONDITIONS		SN54ALS28A			SN74ALS28A			UNIT
PARAMETER			MIN	TYP <sup>†</sup>	MAX	MIN	TYP†	MAX	UNII
VIK	V <sub>CC</sub> = 4.5 V,	I <sub>I</sub> = -18 mA			-1.5			-1.5	V
	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -0.4 \text{ mA}$	V <sub>CC</sub> -2			V <sub>CC</sub> -2			
$V_{OH}$	$V_{CC} = 4.5 \text{ V},$	I <sub>OH</sub> = -1 mA	2.4	3.3					V
	$V_{CC} = 4.5 \text{ V},$	$I_{OH} = -2.6 \text{ mA}$				2.4	3.3		
Va	$V_{CC} = 4.5 \text{ V},$	I <sub>OL</sub> = 12 mA		0.25	0.4		0.25	0.4	V
VOL	$V_{CC} = 4.5 \text{ V},$	$I_{OL} = 24 \text{ mA}$					0.35	0.5	V
lį	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 7 V			0.1			0.1	mA
lіН	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 2.7 V			20			20	μΑ
Ι <sub>ΙL</sub>	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 0.4 V			-0.1			-0.1	mA
lo <sup>‡</sup>	$V_{CC} = 5.5 \text{ V},$	V <sub>O</sub> = 2.25 V	-30		-112	-30		-112	mA
Iссн	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 0 V		1.7	2.8		1.7	2.8	mA
ICCL	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 4.5 V		5.6	9		5.6	9	mA

<sup>&</sup>lt;sup>†</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

#### switching characteristics (see Note 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 5 \text{ V},$ $C_{L} = 50 \text{ pF},$ $R_{L} = 500 \Omega,$ $T_{A} = 25^{\circ}\text{C}$ 'ALS28A TYP		C <sub>L</sub> = 50 R <sub>L</sub> = 50 T <sub>A</sub> = MI			UNIT
<sup>t</sup> PLH	A or B	Y	4	1	16	2	8	·
t <sub>PHL</sub>	A or B	Y	4	1	10	2	7	

NOTE 1: Load circuit and voltage waveforms are shown in Section 1.



<sup>&</sup>lt;sup>‡</sup> The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, los.

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